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## Abstract of the invention

The present invention relates to the field of the use of automated measurement systems in analysis and in invitro diagnosis. In particular, the apparatus described enables automatic quality control and validation of characteristic process engineering parameters, in particular characteristic optical parameters, during the measurement of scattered light signals.

Key for figures:

Fig. 1

10 Detection unit

11 Drive arrangement

Fig. 2

Detection unit

Fig. 3

Plan view

d Side view